

2. (Amended) The spectral ellipsometer as defined in Claim 1, wherein the color-corrected illuminating optical system is a lens doublet or a lens triplet.

3. (Amended) The spectral ellipsometer as defined in Claim 1, wherein the color-corrected illuminating optical system is made of glass having at least one of high transmission in the UV range and an anti-reflection coating.

4. (Amended) The spectral ellipsometer as defined in Claim 1, wherein the color-corrected illuminating optical system is constructed from individual refractive optical elements that are joined with a cement having high transmission in the UV range.

5. (Amended) A spectral ellipsometer comprising: a refractive illuminating optical system for an illuminating ray bundle, coming from an illumination unit, for generating a measurement spot on a surface of a specimen; and a detector unit that receives and detects, as a measured ray bundle, the light reflected from the surface at the location of the measurement spot, wherein the illuminating optical system is color-corrected, and wherein a receiving optical system that is color-corrected is provided for the measured ray bundle.

6. (Amended) The spectral ellipsometer as defined in Claim 5, wherein the color-corrected receiving optical system is a lens doublet or a lens triplet.

7. (Amended) The spectral ellipsometer as defined in Claim 5, wherein the color-corrected receiving optical system is made of glass having at least one of high transmission in the UV range and an anti-reflection coating.

8. (Amended) The spectral ellipsometer as defined in Claim 5, wherein the color-corrected receiving optical system is constructed from individual refractive optical elements that are joined with a cement having high transmission in the UV range.

*sub* *59.* (Amended) The spectral ellipsometer as defined in Claim 1,  
characterized in that it is used to measure material parameters of thin layers  
applied onto the specimen surface.